

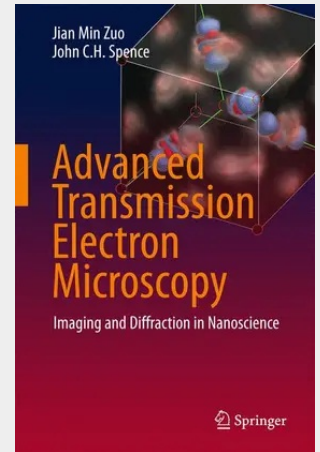
Advanced Transmission Electron Microscopy

Imaging and Diffraction in Nanoscience

This volume expands and updates the coverage in the authors' popular 1992 book, *Electron Microdiffraction*. As the title implies, the focus of the book has changed from electron microdiffraction and convergent beam electron diffraction to all forms of advanced transmission electron microscopy. Special attention is given to electron diffraction and imaging, including high-resolution TEM and STEM imaging, and the application of these methods to crystals, their defects, and nanostructures. The authoritative text summarizes and develops most of the useful knowledge which has been gained over the years from the study of the multiple electron scattering problem, the recent development of aberration correctors and their applications to materials structure characterization, as well as the authors' extensive teaching experience in these areas.

Advanced Transmission Electron Microscopy: Imaging and Diffraction in Nanoscience is ideal for use as an advanced undergraduate or graduatelevel text in support of course materials in Materials Science, Physics or Chemistry departments.

This volume expands and updates the coverage in the authors' popular 1992 book, *Electron Microdiffraction*. As the title implies, the focus of the book has changed from electron microdiffraction and convergent beam electron diffraction to all forms of advanced transmission electron microscopy. Special attention is given to electron diffraction and imaging, including high-resolution TEM and STEM imaging, and the application of these methods to crystals, their defects, and nanostructures. The authoritative text summarizes and develops most of the useful knowledge which has been gained over the years from the study of the multiple electron scattering problem, the recent development of aberration correctors and their applications to materials structure characterization, as well as the authors' extensive teaching experience in these areas. *Advanced Transmission Electron Microscopy: Imaging and Diffraction in Nanoscience* is ideal for use as an advanced undergraduate or graduatelevel text in support of course materials in Materials Science, Physics or Chemistry departments.



139,09 €

129,99 € (zzgl. MwSt.)

Lieferfrist: bis zu 10 Tage

Artikelnummer: 9781493966059

Medium: Buch

ISBN: 978-1-4939-6605-9

Verlag: Springer

Erscheinungstermin: 26.10.2016

Sprache(n): Englisch

Auflage: 1. Auflage 2017

Produktform: Gebunden

Gewicht: 13838 g

Seiten: 729

Format (B x H): 160 x 241 mm

